## Notice of References Cited Application/Control No. 10/781,289 Examiner Paulos M. Natnael Applicatit(s)/Patent Under Reexamination INA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2005/0022249 A1	01-2005	Shibusawa, Toru	725/119
	В	US-2005/0032495 A1	02-2005	Stalf et al.	455/232.1
	U	US-6,094,236 A	07-2000	Abe et al.	348/731
	D	US-5,774,194 A	06-1998	Armbruster, Veit	348/726
	ш	US-2004/0229561 A1	11-2004	Cowley et al.	455/003.01
	F	US-5,258,764 A	11-1993	Malinowski, Frank R.	342/359
	G	US-6,028,647 A	02-2000	Fukai et al.	348/731
	Н	US-6,020,936 A	02-2000	Brekelmans, Johannes H.A.	348/725
	1	US-2004/0259512 A1	12-2004	Busson et al.	455/190.1
	J	US-6,609,039 B1	08-2003	Schoen, Neil Charles	700/94
	К	US-5,926,744 A	07-1999	Fukuzawa et al.	725/69
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S	·				
	Т			-		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	×							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.